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| Thu, 20 Dec | 16:15 — 17:50 | TEST | Management and Marketing  Silenko A.N.  A-100 |
| Sat, 22 Dec | 09:00 — 12:00 | TEST | Life Safety  Pripachkin D.A.  T-209 |
| Mon, 24 Dec | 09:00 — 12:00 | ATT | Sensors Based on Micro- and Nanotechnologies  Podlepetskiy B.I.  V-411 |
| Mon, 24 Dec | 12:00 — 15:00 | ATT | Software Support of Modern Microprocessors and Microcontrollers  Shagurin I.I.  D-311 |
| Tue, 25 Dec | 09:00 — 12:00 | TEST | Quantum Radiophysics  Larkin A.I.  K-1117 |
| Tue, 25 Dec | 12:00 — 15:00 | TEST | Microelectronic Radio Devices  Bocharov Y.I.  D-311 |
| Thu, 27 Dec | 09:00 — 12:00 | TEST | Information Measurement Systems  Belyakov V.V.  D-311 |
| Thu, 27 Dec | 12:00 — 15:00 | ATT | Reliability and Radiation Resistance of Integrated Circuits  Zebrev G.I.  D-303 |
| Fri, 28 Dec | 12:00 — 15:00 | TEST | Scientific Research Work  Shagurin I.I.  dep.27 |
| Fri, 28 Dec | 15:00 — 18:00 | ATT | Principles of Optoelectronics  Voronov Y.A.  402 |
| Thu, 10 Jan | 09:00 — 13:00 | EXAM | Software Support of Modern Microprocessors and Microcontrollers  Shagurin I.I.  T-102 |
| Mon, 14 Jan | 09:00 — 13:00 | EXAM | Sensors Based on Micro- and Nanotechnologies  Podlepetskiy B.I.  T-102 |
| Sat, 19 Jan | 09:00 — 13:00 | EXAM | Principles of Optoelectronics  Voronov Y.A.  V-417 |
| Wed, 23 Jan | 09:00 — 13:00 | EXAM | Reliability and Radiation Resistance of Integrated Circuits  Zebrev G.I.  D-311 |